

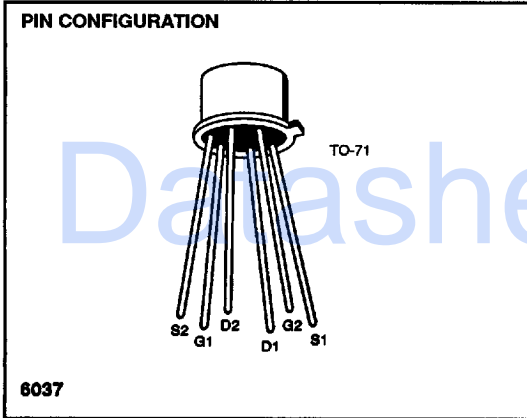


# Dual N-Channel JFET General Purpose Amplifier

2N5196 - 2N5199

T.27-27

2N5196 - 2N5199



**ABSOLUTE MAXIMUM RATINGS**

(T<sub>A</sub> = 25°C unless otherwise noted)

Gate-Source or Gate-Drain Voltage (Note 1) ..... -50V  
 Gate Current (Note 1) ..... 50mA  
 Storage Temperature Range ..... -65°C to +200°C  
 Operating Temperature Range ..... -55°C to +150°C  
 Lead Temperature (Soldering, 10sec) ..... +300°C

	One Side	Both Sides
Power Dissipation (T <sub>A</sub> = 85°C)	250mW	500mW
Derating	2.6mW/°C	4.3mW/°C

NOTE: Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions above those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

**ORDERING INFORMATION**

Part	Package	Temperature Range
2N5196	Hermetic TO-71	-55°C to +150°C
2N5197	Hermetic TO-71	-55°C to +150°C
2N5198	Hermetic TO-71	-55°C to +150°C
X2N5198	Sorted Chips in Carriers	-55°C to +150°C
2N5199	Hermetic TO-71	-55°C to +150°C
X2N5199	Sorted Chips in Carriers	-55°C to +150°C

**ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = 25°C unless otherwise specified)**

SYMBOL	PARAMETER	MIN	MAX	UNITS	TEST CONDITIONS
I <sub>oss</sub>	Gate Reverse Current		-25	pA	V <sub>GS</sub> = -30V, V <sub>DS</sub> = 0 T <sub>A</sub> = 150°C
			-50	nA	
BV <sub>GS</sub>	Gate-Source Breakdown Voltage	-50			I <sub>G</sub> = -1μA, V <sub>DS</sub> = 0
V <sub>GS(off)</sub>	Gate-Source Cutoff Voltage	-0.7	-4	V	V <sub>DS</sub> = 20V, I <sub>D</sub> = 1nA
V <sub>GS</sub>	Gate-Source Voltage	-0.2	-3.8		V <sub>DS</sub> = 20V, I <sub>D</sub> = 200μA
I <sub>G</sub>	Gate Operating Current		-15	pA	T <sub>A</sub> = 125°C
			-15	nA	
I <sub>DSS</sub>	Saturation Drain Current (Note 2)	0.7	7	mA	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0
g <sub>fs</sub>	Common-Source Forward Transconductance (Note 2)	1000	4000		V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0 V <sub>DS</sub> = 20V, I <sub>D</sub> = 200μA V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0 V <sub>DS</sub> = 20V, I <sub>D</sub> = 200μA
g <sub>fs</sub>	Common-Source Forward Transconductance (Note 2)	700	1600	μS	
g <sub>os</sub>	Common-Source Output Conductance (Note 2)		50		
g <sub>os</sub>	Common-Source Output Conductance (Note 2)		4		
C <sub>iss</sub>	Common-Source Input Capacitance (Note 4)		6	pF	f = 1MHz
C <sub>rss</sub>	Common-Source Reverse Transfer Capacitance (Note 4)		2		
NF	Spot Noise Figure (Note 4)		0.5	dB	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0 f = 100Hz, R <sub>G</sub> = 10MΩ
$\bar{e}_n$	Equivalent Input Noise Voltage (Note 4)		20	nV/√Hz	f = 1kHz

2N5196 - 2N5199

**2N5196 - 2N5199**



T-27-27

**ELECTRICAL CHARACTERISTICS** (Continued) ( $T_A = 25^\circ\text{C}$  unless otherwise specified)

SYMBOL	PARAMETER	2N5196		2N5197		2N5198		2N5199		UNITS	TEST CONDITIONS	
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX			
$ I_{G1} - I_{G2} $	Differential Gate Current		5		5		5		5	nA	$V_{DG} = 20V, I_D = 200\mu A$ $T_A = 125^\circ\text{C}$	
$I_{DSS1} / I_{DSS2}$	Saturation Drain Current Ratio (Note 2)	0.95	1	0.95	1	0.95	1	0.95	1		$V_{DS} = 20V, V_{GS} = 0V$	
$g_{fs1} / g_{fs2}$	Transconductance Ratio (Note 2)	0.97	1	0.97	1	0.95	1	0.95	1		$f = 1\text{kHz}$	
$ V_{GS1} - V_{GS2} $	Differential Gate-Source Voltage		5		5		10		15	mV	$V_{DG} = 20V, I_D = 200\mu A$	
$\frac{\Delta  V_{GS1} - V_{GS2} }{\Delta T}$	Gate-Source Differential Voltage Change with Temperature (Note 3)		5		10		20		40	$\mu V / ^\circ\text{C}$		$T_A = 25^\circ\text{C}$ $T_B = 125^\circ\text{C}$
			5		10		20		40			$T_A = -55^\circ\text{C}$ $T_B = 25^\circ\text{C}$
$ g_{os1} - g_{os2} $	Differential Output Conductance		1		1		1		1	$\mu s$	$f = 1\text{kHz}$	

- NOTES:** 1. Per transistor.  
 2. Pulse test required, pulsewidth = 300 $\mu s$ , duty cycle <3%  
 3. Measured at endpoints  $T_A$  and  $T_B$ .  
 4. For design reference only, not 100% tested.